IAP11 Rec'd PCT/PTO 02 AUG 2006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Yuji MIYAHARA et al.

Mail Stop: PCT

Serial No. NEW

Attorney Docket No. 2006 1275A

Filed August 2, 2006

GENE DETECTION FIELD-EFFECT DEVICE AND METHOD OF ANALYZING GENE POLYMORPHISM THEREWITH [Corresponding to PCT/JP2005/001987 Filed February 3, 2005]

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 CFR 1.56, 1.97 and 1.98, Applicants request consideration of the references listed on attached form PTO-1449 and any additional information identified below in paragraph 3. A legible copy of each reference listed on the Form PTO-1449 is enclosed, except a copy is not provided for:

	[X]	each U.S. Patent and U.S. Patent application publication;					
	0	each reference previously cited in the international application PCT/; and/or					
		each reference previously cited in prior parent application Serial No.					
1a.	[X] This Information Disclosure Statement is submitted:						
	within three months of the filing date (or of entry into the National Stage) of the above-entitled application, or						

10/587941 IAP11 Rec'd PCT/PTO 02 AUG 2006

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

and thus no certification and/or fee is required.

1b.	[] This Information Disclosure Statement is submitted							
	after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:							
	(1) [] the certification of paragraph 2 below is provided, or							
	(2) [] th	ne fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.						
1c.	[] This Information Disclosure Statement is submitted:							
	after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:							
	the certification of paragraph 2 below is provided, and							
	the fee	e of \$180.00 specified in 37 CFR 1.17(p) is enclosed.						
2.	It is hereby certified							
	a. []	that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or						
	b. []	that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.						

10/587941

IAP11 Rec'd PCT/PTO 02 AUG 2006

- Consideration of the following list of additional information (including any copending or 3. abandoned U.S. application, prior uses and/or sales, etc.) is requested.
- 4. For each non-English language reference listed on the attached form PTO-1449, reference is made to:
 - a full or partial English language translation submitted herewith, a. []
 - b. [] a foreign patent office search report (in the English language) submitted herewith,
 - the concise explanation contained in the specification of the present application c. [] at page,
 - d. [] the concise explanation set forth in the attached English language abstract,
 - e. [] the concise explanation set forth below or on a separate sheet attached to the reference:
- 5. [X] A foreign patent office search report citing one or more of the references is enclosed.

Respectfully submitted,

Yuji MIYAHARA et al.

By <u>Nau Cheell</u> Warren M. Cheek, Jr. Registration No. 33,367

Attorney for Applicants

WMC/dlk Washington, D.C. 20006-1021 Telephone (202) 721-8200 Facsimile (202) 721-8250 August 2, 2006

10/50/744

Sheet 1 of 1			INFORMA	TION DISCLO	SURE SAPENENT	Rec'd	PCT/	PTO 02	ALIG 200	<u></u>		
FORM PTO 1449 (modified)				ATTY DOC 2006_12	KET NO.		SERIAL I		1 00 500 1	0		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Yuji MIYAHARA et al.								
	LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE			GROUP				
Date Submitted to PTO: August 2, 2006					August 2, 2006 S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT DATE NUMBER			NAME CLASS		ASS	SUBCLASS	FILING DATE IF APPROPRIATE				
	AA	2003/0148301	8/2003	Ao	no et al.				Corresponds to AF			
	AB	<u></u>										
	AC											
	AD								11			
		<u> </u>	FORE	EIGN PATENT	DOCUMENTS	-1		1				
		DOCUMENT NUMBER	DATE	C	DUNTRY	CL	ASS	SUBCLASS	TRANSL/ YES	ATION NO		
000000000000000000000000000000000000000		<u>2002</u> 27.2463	0/2002	600000000000000000000000000000000000000		000000000000000000000000000000000000000	000000000000000000000000000000000000000	000000000000000000000000000000000000000		000000000000000000000000000000000000000		
	AF	2001-42498	6/2001		wo							
	AG											
		OTHER	DOCUMENT(S) (/	ncluding Auth	or, Title, Date, Pertin	nent Pages	s, Etc.)					
	AH Y. Miyahara et al., "Potentiometric Detection of DNA Molecules Using Field Effect Transistor", The Japan Society of Applied Physics., No. 3, p. 1180, 30a-S-2, 2003 (English translation enclosed).											
	Al	Y. Miyahara et al., "Biochip Using Micromachining Technology", Journal of Institute of Electrostatics Japan, Vol. 27, No. 6, pp. 268-272, 2003 (English translation enclosed).										
	AJ	T. Sakata et al.,Detection of DNA Hybridization by Genetic Transistor", The Japan Society of Applied Physics, No. 3, p. 1179, 30a-S-1, 2003 (English translation enclosed).										
	AK	T. Sakata et al., Potentiometric Detection of DNA Molecules Using Genetic Field Effect Transistor", Denki Gakkai Kenkyukai Shiryo Chemical Sensor Kenkyukai, pp. 1-5, CH5-03-51-55, 2003 (English translation enclosed).										
	AL											
	АМ				•	· <u> · ·</u>			<u> </u>			
EXAMINER	/C	hristopher Babic/		DATE CONSIDERED 05/20/2009								

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy this form with next communication to applicant.